

Lecture #4

ANNOUNCEMENTS

- Prof. King will not hold office hours this week, but will hold an extra office hour next Mo (2/3) from 11AM-12:30PM
- Quiz #1 will be given at the **beginning** of class on Th 2/6
 - covers material in Chapters 1 & 2 (HW#1 & HW#2)
 - closed book; one page of notes allowed

OUTLINE

- Drift (Chapter 3.1)
 - » carrier motion
 - » mobility
 - » resistivity

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Nondegenerately Doped Semiconductor

- Recall that the expressions for n and p were derived using the Boltzmann approximation, *i.e.* we assumed

$$E_v + 3kT \leq E_F \leq E_c - 3kT$$

The semiconductor is said to be ***nondegenerately doped*** in this case.

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Degenerately Doped Semiconductor

- If a semiconductor is very heavily doped, the Boltzmann approximation is not valid.

In Si at $T=300\text{K}$: $E_c - E_F < 3kT$ if $N_D > 1.6 \times 10^{18} \text{ cm}^{-3}$

$$E_F - E_v < 3kT \text{ if } N_A > 9.1 \times 10^{17} \text{ cm}^{-3}$$

The semiconductor is said to be **degenerately doped** in this case.

$$E_v + 3kT \leq E_F \leq E_c - 3kT$$

Band Gap Narrowing

- If the dopant concentration is a significant fraction of the silicon atomic density, the energy-band structure is perturbed

→ the band gap is reduced by ΔE_G

$$N = 10^{18} \text{ cm}^{-3}:$$

$$N = 10^{19} \text{ cm}^{-3}:$$

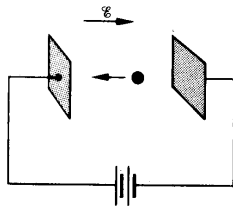
Free Carriers in Semiconductors

- Three primary types of carrier action occur inside a semiconductor:
 - drift
 - diffusion
 - recombination-generation

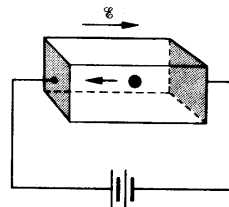
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Electrons as Moving Particles



$$F = (-q)\mathcal{E} = m_0 a$$



$$F = (-q)\mathcal{E} = m_n^* a$$

where

m_n^* is the electron effective mass

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Carrier Effective Mass

In an electric field, \mathcal{E} , an electron or a hole accelerates:

$$a = \frac{-q\mathcal{E}}{m_n} \quad \text{electrons}$$

$$a = \frac{q\mathcal{E}}{m_p} \quad \text{holes}$$

Electron and hole conductivity effective masses:

	Si	Ge	GaAs
m_n/m_0	0.26	0.12	0.068
m_p/m_0	0.39	0.30	0.50

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Thermal Velocity

Average electron or hole kinetic energy $= \frac{3}{2}kT = \frac{1}{2}m^*v_{th}^2$

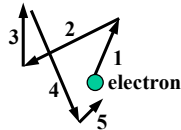
$$v_{th} = \sqrt{\frac{3kT}{m^*}} = \sqrt{\frac{3 \times 0.026 \text{ eV} \times (1.6 \times 10^{-19} \text{ J/eV})}{0.26 \times 9.1 \times 10^{-31} \text{ kg}}}$$
$$= 2.3 \times 10^5 \text{ m/s} = 2.3 \times 10^7 \text{ cm/s}$$

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Carrier Scattering

- **Mobile electrons and atoms in the Si lattice are always in random thermal motion.**
 - Electrons make frequent collisions with the vibrating atoms
 - “lattice scattering” or “phonon scattering”
 - increases with increasing temperature
 - Average velocity of thermal motion for electrons: $\sim 10^7$ cm/s @ 300K
- **Other scattering mechanisms:**
 - deflection by ionized impurity atoms
 - deflection due to Coulombic force between carriers
 - “carrier-carrier scattering”
 - only significant at high carrier concentrations
- **The net current in any direction is zero, if no electric field is applied.**

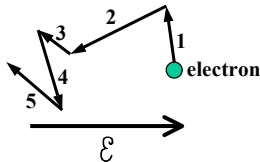


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Carrier Drift

- **When an electric field (e.g. due to an externally applied voltage) is applied to a semiconductor, mobile charge-carriers will be accelerated by the electrostatic force. This force superimposes on the random motion of electrons:**



- **Electrons *drift* in the direction opposite to the electric field**
→ **current flows**
- ❖ **Because of scattering, electrons in a semiconductor do not achieve constant acceleration. However, they can be viewed as quasi-classical particles moving at a constant average *drift velocity* v_d**

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Electron Momentum

- With every collision, the electron loses momentum

$$m_n^* v_d$$

- Between collisions, the electron gains momentum

$$(-q)\mathcal{E}\tau_{mn}$$

where τ_{mn} = average time between scattering events

Carrier Mobility

$$m_n^* v_d = (-q)\mathcal{E}\tau_{mn}$$

$$|v_d| = q\mathcal{E}\tau_{mn} / m_n^* = \mu_n \mathcal{E}$$

- $\mu_n \equiv [q\tau_{mn} / m_n^*]$ is the **electron mobility**

Similarly, for holes: $|v_d| = q\mathcal{E}\tau_{mp} / m_p^* \equiv \mu_p \mathcal{E}$

- $\mu_p \equiv [q\tau_{mp} / m_p^*]$ is the **hole mobility**

Electron and Hole Mobilities

μ has the dimensions of v/\mathcal{E} : $\left[\frac{\text{cm/s}}{\text{V/cm}} = \frac{\text{cm}^2}{\text{V}\cdot\text{s}} \right]$

Electron and hole mobilities of selected intrinsic semiconductors ($T=300\text{K}$)

	Si	Ge	GaAs	InAs
μ_n ($\text{cm}^2/\text{V}\cdot\text{s}$)	1400	3900	8500	30000
μ_p ($\text{cm}^2/\text{V}\cdot\text{s}$)	470	1900	400	500

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Example: Drift Velocity Calculation

Find the hole drift velocity in an intrinsic Si sample for $\mathcal{E} = 10^3 \text{ V/cm}$.

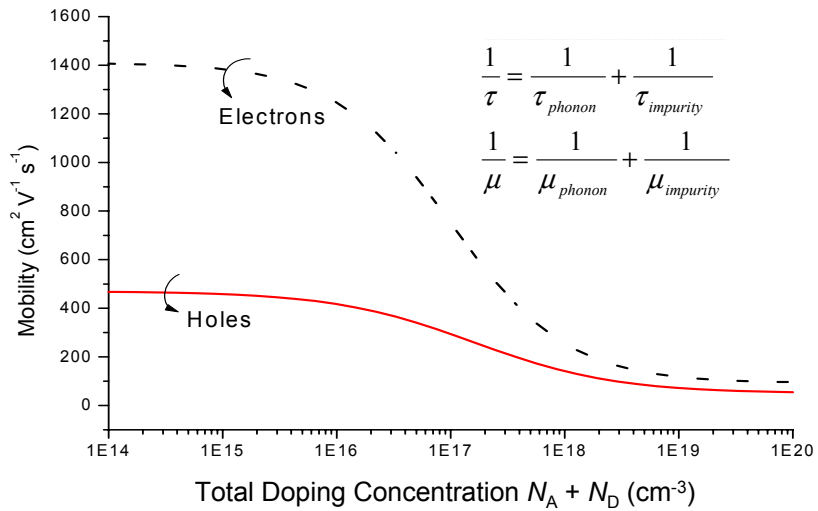
What is τ_{mp} , and what is the distance traveled between collisions?

Solution:

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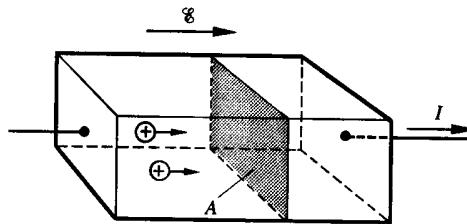
Mobility Dependence on Doping



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Drift Current



$v_d t A$ = volume from which all holes cross plane in time t

$p v_d t A$ = # of holes crossing plane in time t

$q p v_d t A$ = charge crossing plane in time t

$q p v_d A$ = charge crossing plane per unit time = hole current

➔ Hole current per unit area $J = q p v_d$

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Conductivity and Resistivity

$$J_{n,drift} = -qnv = qn\mu_n \mathcal{E}$$

$$J_{p,drift} = qp v = qp\mu_p \mathcal{E}$$

$$J_{drift} = J_{n,drift} + J_{p,drift} = \sigma \mathcal{E} = (qn\mu_n + qp\mu_p) \mathcal{E}$$

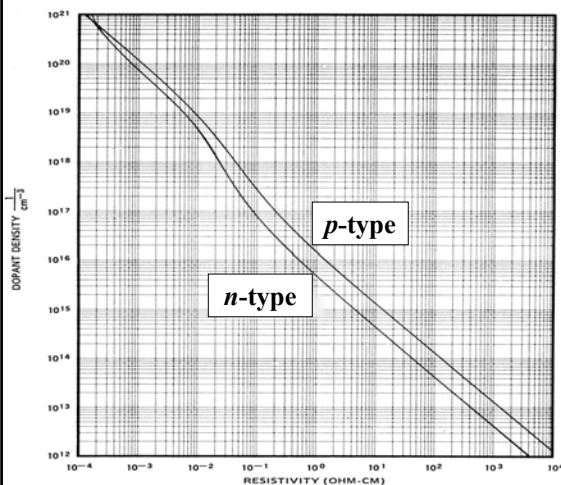
Conductivity of a semiconductor is $\sigma \equiv qn\mu_n + qp\mu_p$

Resistivity $\rho \equiv 1 / \sigma$ (Unit: ohm-cm)

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Resistivity Dependence on Doping



For n-type mat'l:

$$\rho \cong \frac{1}{qn\mu_n}$$

For p-type mat'l:

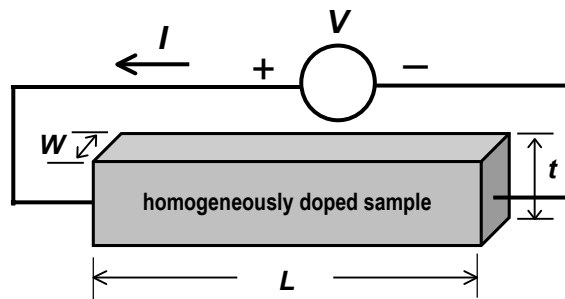
$$\rho \cong \frac{1}{qp\mu_p}$$

Note: This plot does not apply for compensated material!

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Electrical Resistance



Resistance

$$R \equiv \frac{V}{I} = \rho \frac{L}{Wt}$$

(Unit: ohms)

where ρ is the resistivity

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Example

Consider a Si sample doped with $10^{16}/\text{cm}^3$ Boron.
What is its resistivity?

Answer:

$$N_A = 10^{16}/\text{cm}^3, N_D = 0 \quad (N_A \gg N_D \rightarrow \text{p-type})$$

$$\rightarrow p \approx 10^{16}/\text{cm}^3 \quad \text{and} \quad n \approx 10^4/\text{cm}^3$$

$$\begin{aligned} \rho &= \frac{1}{qn\mu_n + qp\mu_p} \cong \frac{1}{qp\mu_p} \\ &= [(1.6 \times 10^{-19})(10^{16})(450)]^{-1} = 1.4 \, \Omega\text{-cm} \end{aligned}$$

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Example: Dopant Compensation

Consider the same Si sample, doped *additionally* with $10^{17}/\text{cm}^3$ Arsenic. What is its resistivity?

Answer:

$$N_A = 10^{16}/\text{cm}^3, N_D = 10^{17}/\text{cm}^3 \quad (N_D \gg N_A \rightarrow \text{n-type})$$

$$\rightarrow n \approx 9 \times 10^{16}/\text{cm}^3 \quad \text{and} \quad p \approx 1.1 \times 10^3/\text{cm}^3$$

$$\rho = \frac{1}{qn\mu_n + qp\mu_p} \cong \frac{1}{qn\mu_n}$$

$$= \left[(1.6 \times 10^{-19})(9 \times 10^{16})(600) \right]^{-1} = 0.12 \, \Omega\text{-cm}$$

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Summary

- Electrons and holes moving under the influence of an electric field can be modelled as quasi-classical particles with average drift velocity

$$|v_d| = \mu \mathcal{E}$$

- The conductivity of a semiconductor is dependent on the carrier concentrations and mobilities

$$\sigma = qn\mu_n + qp\mu_p$$

- Resistivity $\rho = \frac{1}{\sigma} = \frac{1}{qn\mu_n + qp\mu_p}$

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